



09/692,606

COFC

PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Jack Oon Chu, et al.

Docket: 17178

Patent No.: 6,890,835

Dated: August 04, 2005

Issued: May 10, 2005

For: LAYER TRANSFER OF LOW DEFECT SIGE
USING AN ETCH-BACK PROCESS

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

REQUEST FOR CERTIFICATE OF CORRECTION

Sir:

It appears that errors have been introduced in the course of printing the Patent issued in the above application, and it is respectfully requested that the Commissioner issue a Certificate of Correction in the following respects:

[57] ABSTRACT (Last Sentence)

“contact of the SiGe/Si” should read -- contact of the SiGe/Si –

Respectfully submitted,

Certificate
AUG 12 2005
of Correction


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UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO : **6,890,835** *B1*

APPLICATION NO : **09/692,606**

ISSUE DATE : **May 10, 2005**

INVENTOR(S) : **Jack Oon Chu, et al.**

It is certified that an error appears or errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

[57] ABSTRACT (Last Sentence)

“contact of the SiGe/Si” should read -- contact of the SiGe/Si --

MAILING ADDRESS OF SENDER:

PATENT NO. **6,890,835**

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